

ZXMN3G32DN8

30V SO8 dual N-channel enhancement mode MOSFET

Summary

$V_{(BR)DSS}$	$R_{DS(on)}$ (Ω)	I_D (A)
30	0.028 @ $V_{GS} = 10V$	7.1
	0.045 @ $V_{GS} = 4.5V$	5.6



Description

This new generation Trench MOSFET from Zetex features low on-resistance and fast switching speed.

Features

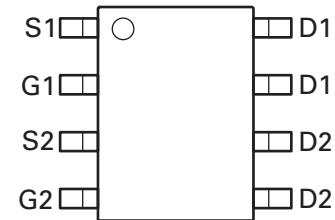
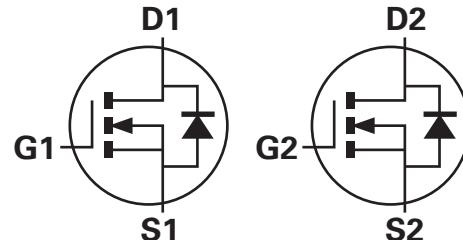
- Low on-resistance
- 4.5V gate drive capability
- Fast switching bullet

Applications

- DC-DC Converters
- Power management functions
- Motor Control
- Backlighting

Ordering information

DEVICE	Reel size (inches)	Tape width (mm)	Quantity per reel
ZXMN3G32DN8TA	7	12	500



Device marking

ZXMN

3G32D

ZXMN3G32DN8

Absolute maximum ratings

Parameter	Symbol	Limit	Unit
Drain source voltage	V_{DSS}	30	V
Gate source voltage	V_{GS}	± 20	V
Continous Drain Current @ $V_{GS}=10$; $T_A=25^\circ C$ ^(b) @ $V_{GS}=10$; $T_A=70^\circ C$ ^(b) @ $V_{GS}=10$; $T_A=25^\circ C$ ^(a)	I_D	7.1 5.7 5.5	A A A
Pulsed drain current ^(c)	I_{DM}	33.6	A
Continuous source current (body diode) ^(b)	I_S	3.1	A
Pulsed source current (body diode) ^(c)	I_{SM}	33.6	A
Power dissipation at $T_A = 25^\circ C$ ^{(a)(d)}	P_D	1.25	W
Linear derating factor		10	$mW/^\circ C$
Power dissipation at $T_A = 25^\circ C$ ^{(a)(e)}	P_D	1.8	W
Linear derating factor		14	$mW/^\circ C$
Power dissipation at $T_A = 25^\circ C$ ^{(b)(d)}	P_D	2.1	W
Linear derating factor		17	$mW/^\circ C$
Operating and storage temperature range	T_j, T_{stg}	-55 to 150	$^\circ C$

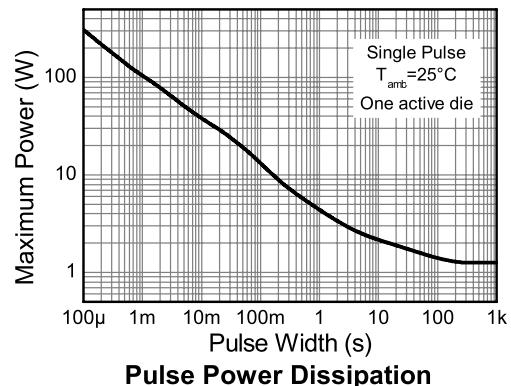
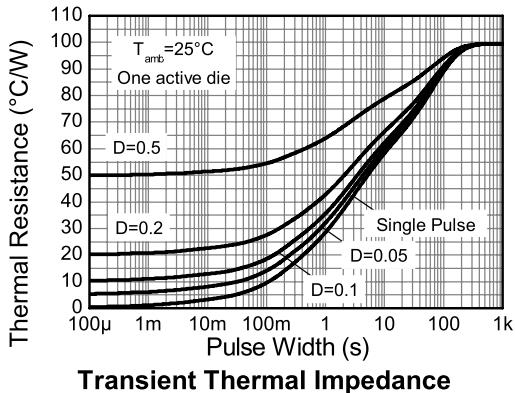
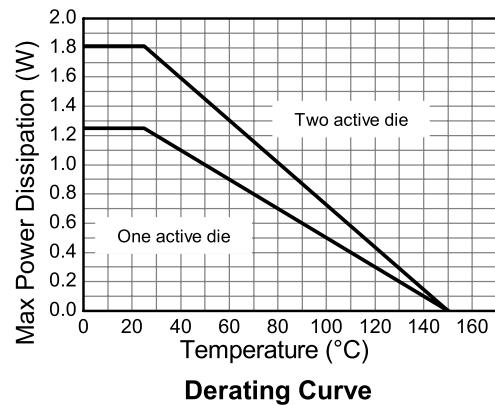
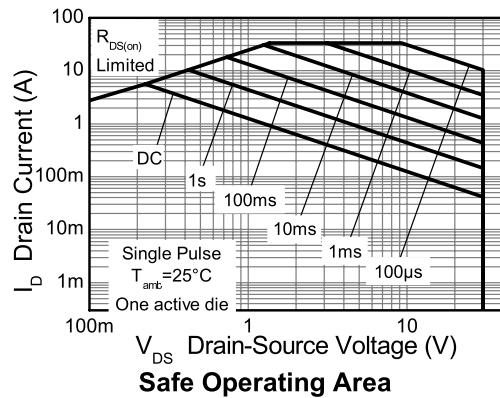
Thermal resistance

Parameter	Symbol	Limit	Unit
Junction to ambient ^{(a)(d)}	$R_{\Theta JA}$	100	$^\circ C/W$
Junction to ambient ^{(a)(e)}	$R_{\Theta JA}$	70	$^\circ C/W$
Junction to ambient ^{(b)(d)}	$R_{\Theta JA}$	60	$^\circ C/W$
Junction to lead ^(f)	$R_{\Theta JL}$	51	$^\circ C/W$

NOTES:

- (a) For a device surface mounted on 25mm x 25mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions.
- (b) For a device surface mounted on FR4 PCB measured at $t \leq 10$ sec.
- (c) Repetitive rating - 25mm x 25mm FR4 PCB, $D=0.02$, pulse width 300 μ s - pulse width limited by maximum junction temperature.
- (d) For a dual device with one active die.
- (e) For a device with two active die running at equal power.
- (f) Thermal resistance from junction to solder-point (at end of drain lead).

Thermal characteristics



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Electrical characteristics (at $T_{amb} = 25^\circ C$ unless otherwise stated)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Conditions
Static						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	30			V	$I_D = 250\mu A, V_{GS} = 0V$
Zero Gate Voltage Drain Current	I_{DSS}			0.5	μA	$V_{DS} = 30V, V_{GS} = 0V$
Gate-Body Leakage	I_{GSS}			100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$
Gate-Source Threshold Voltage	$V_{GS(th)}$	1.0		3.0	V	$I_D = 250\mu A, V_{DS} = V_{GS}$
Static Drain-Source On-State Resistance (*)	$R_{DS(on)}$			0.028 0.045	Ω	$V_{GS} = 10V, I_D = 6.0A$ $V_{GS} = 4.5V, I_D = 4.9A$
Forward Transconductance ^(*) (†)	g_{fs}		12		S	$V_{DS} = 15V, I_D = 6.0A$
Dynamic (†)						
Input Capacitance	C_{iss}		472		pF	$V_{DS} = 15V, V_{GS} = 0V$ $f = 1MHz$
Output Capacitance	C_{oss}		178		pF	
Reverse Transfer Capacitance	C_{rss}		65		pF	
Switching (‡)(†)						
Turn-On-Delay Time	$t_{d(on)}$		2.5		ns	$V_{DD} = 15V, I_D = 1A$ $R_G \geq 6.0\Omega, V_{GS} = 10V$
Rise Time	t_r		3.1		ns	
Turn-Off Delay Time	$t_{d(off)}$		14		ns	
Fall Time	t_f		9.7		ns	
Total Gate Charge	Q_g		10.5		nC	$V_{DS} = 15V, V_{GS} = 10V$ $I_D = 6A$
Gate-Source Charge	Q_{gs}		1.86		nC	
Gate Drain Charge	Q_{gd}		2.3		nC	
Source-drain diode						
Diode Forward Voltage ^(*)	V_{SD}		0.68	1.2	V	$T_j = 25^\circ C, I_S = 1.7A, V_{GS} = 0V$

NOTES:

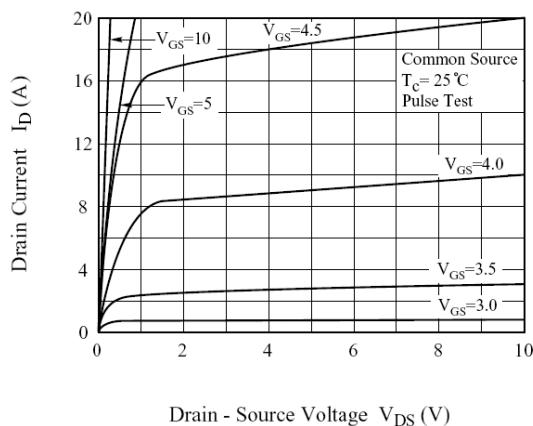
(*) Measured under pulsed conditions. Pulse width $\leq 300\mu s$; duty cycle $\leq 2\%$.

(†) For design aid only, not subject to production testing

(‡) Switching characteristics are independent of operating junction temperature.

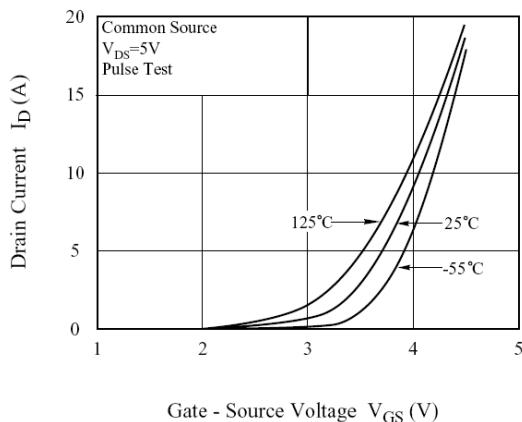
Typical characteristics

Fig1. I_D - V_{DS}



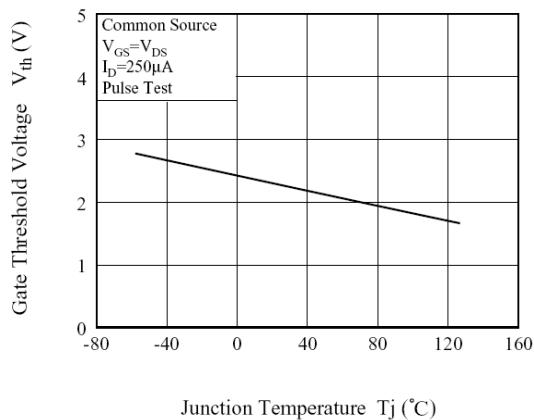
Drain - Source Voltage V_{DS} (V)

Fig3. I_D - V_{GS}



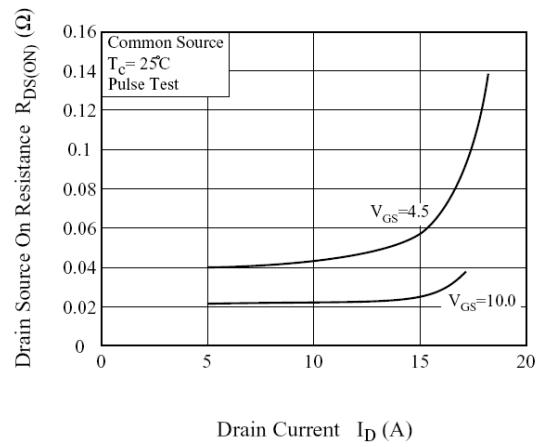
Gate - Source Voltage V_{GS} (V)

Fig5. V_{th} - T_j



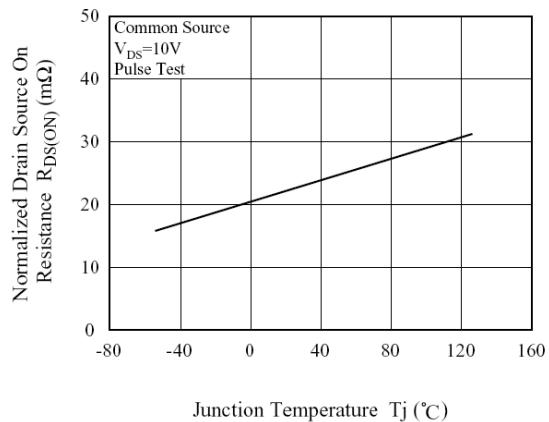
Junction Temperature T_j ($^\circ\text{C}$)

Fig2. $R_{DS(on)}$ - I_D



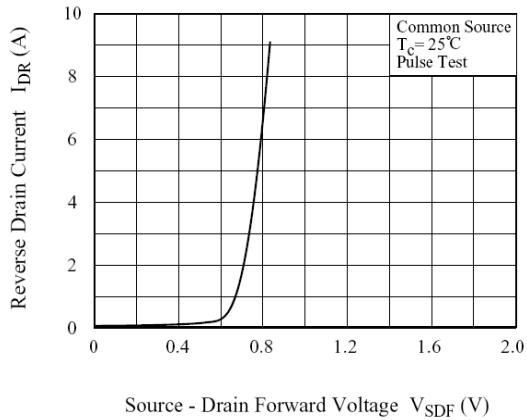
Drain Current I_D (A)

Fig4. $R_{DS(on)}$ - T_j



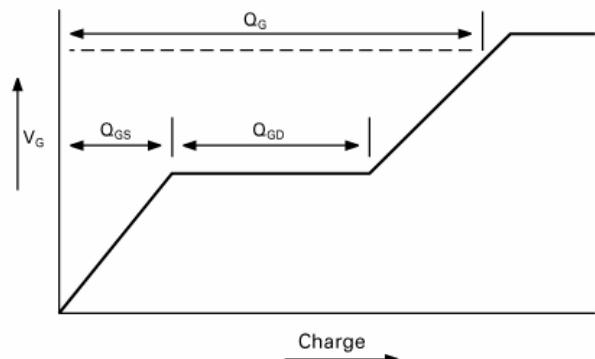
Junction Temperature T_j ($^\circ\text{C}$)

Fig6. I_{DR} - V_{SDF}

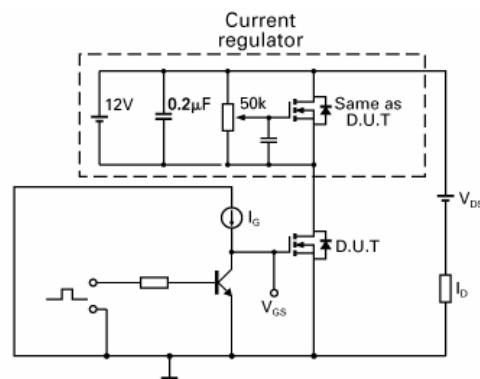


Source - Drain Forward Voltage V_{SDF} (V)

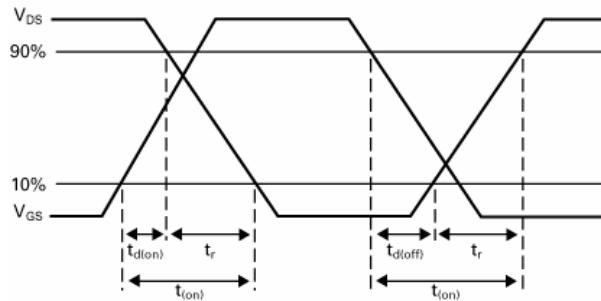
Test circuits



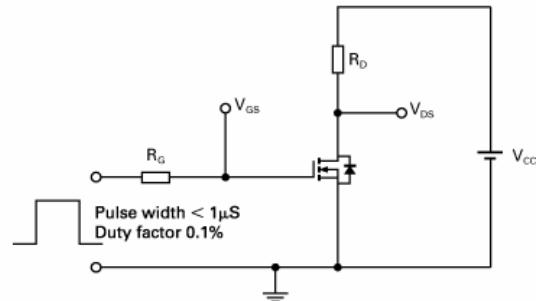
Basic gate charge waveform



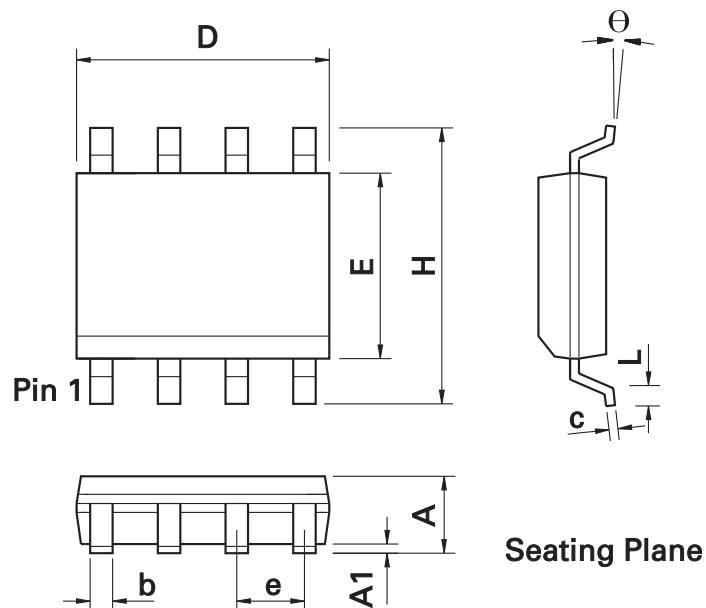
Gate charge test circuit



Switching time waveforms



Switching time test circuit

Package outline - SO8

DIM	Inches		Millimeters		DIM	Inches		Millimeters	
	Min.	Max.	Min.	Max.		Min.	Max.	Min.	Max.
A	0.053	0.069	1.35	1.75	e	0.050 BSC		1.27 BSC	
A1	0.004	0.010	0.10	0.25	b	0.013	0.020	0.33	0.51
D	0.189	0.197	4.80	5.00	c	0.008	0.010	0.19	0.25
H	0.228	0.244	5.80	6.20	Θ	0°	8°	0°	8°
E	0.150	0.157	3.80	4.00	h	0.010	0.020	0.25	0.50
L	0.016	0.050	0.40	1.27	-	-	-	-	-

Note: Controlling dimensions are in inches. Approximate dimensions are provided in millimeters

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